

TECHNICAL REPORT

CISPR 16-4-3

First edition
2003-11

INTERNATIONAL SPECIAL COMMITTEE ON RADIO INTERFERENCE

Specification for radio disturbance and immunity measuring apparatus and methods –

Part 4-3:

Uncertainties, statistics and limit modelling – Statistical considerations in the determination of EMC compliance of mass-produced products

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

**SPECIFICATION FOR RADIO DISTURBANCE
AND IMMUNITY MEASURING APPARATUS AND METHODS –****Part 4-3: Uncertainties, statistics and limit modelling –
Statistical considerations in the determination
of EMC compliance of mass-produced products**

FOREWORD

- 1) The International Electrotechnical Commission (IEC) is a worldwide organization for standardization comprising all national electrotechnical committees (IEC National Committees). The object of IEC is to promote international co-operation on all questions concerning standardization in the electrical and electronic fields. To this end and in addition to other activities, IEC publishes International Standards, Technical Specifications, Technical Reports, Publicly Available Specifications (PAS) and Guides (hereafter referred to as "IEC Publication(s)"). Their preparation is entrusted to technical committees; any IEC National Committee interested in the subject dealt with may participate in this preparatory work. International, governmental and non-governmental organizations liaising with the IEC also participate in this preparation. IEC collaborates closely with the International Organization for Standardization (ISO) in accordance with conditions determined by agreement between the two organizations.
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The main task of IEC technical committees is to prepare International Standards. However, a technical committee may propose the publication of a technical report when it has collected data of a different kind from that which is normally published as an International Standard, for example "state of the art".

This first edition of CISPR 16-4-3, together with CISPR 16-4-1, CISPR 16-4-4 and the second edition of CISPR 16-3, cancels and replaces the first edition of CISPR 16-3, published in 2000, and its amendment 1 (2002). It contains the relevant clauses of CISPR 16-3 without technical changes.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

A bilingual version of this publication may be issued at a later date.

The committee has decided that the contents of this publication will remain unchanged until 2004. At this date, the publication will be

- reconfirmed;
- withdrawn;
- replaced by a revised edition, or
- amended.

The text of this publication is based on the following documents:

Recommendation 46/1 – p/o CISPR. 11, 1990; Report 48 – p/o CISPR 8B, 1975; Report 59: CIS/A(Sec)58 + CIS/A(Sec)58A, 1983.

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INTRODUCTION

CISPR 16-1, CISPR 16-2, CISPR 16-3 and CISPR 16-4 have been reorganised into 14 parts, to accommodate growth and easier maintenance. The new parts have also been renumbered. See the list given below.

Old CISPR 16 publications		New CISPR 16 publications	
CISPR 16-1	Radio disturbance and immunity measuring apparatus	CISPR 16-1-1	Measuring apparatus
		CISPR 16-1-2	Ancillary equipment – Conducted disturbances
		CISPR 16-1-3	Ancillary equipment – Disturbance power
		CISPR 16-1-4	Ancillary equipment – Radiated disturbances
		CISPR 16-1-5	Antenna calibration test sites for 30 MHz to 1 000 MHz
CISPR 16-2	Methods of measurement of disturbances and immunity	CISPR 16-2-1	Conducted disturbance measurements
		CISPR 16-2-2	Measurement of disturbance power
		CISPR 16-2-3	Radiated disturbance measurements
		CISPR 16-2-4	Immunity measurements
CISPR 16-3	Reports and recommendations of CISPR	CISPR 16-3	CISPR technical reports
		CISPR 16-4-1	Uncertainties in standardised EMC tests
		CISPR 16-4-2	Measurement instrumentation uncertainty
		CISPR 16-4-3	Statistical considerations in the determination of EMC compliance of mass-produced products
CISPR 16-4	Uncertainty in EMC measurements	CISPR 16-4-4	Statistics of complaints and a model for the calculation of limits

More specific information on the relation between the 'old' CISPR 16-3 and the present 'new' CISPR 16-4-3 is given in the table after this introduction (TABLE RECAPITULATING CROSS REFERENCES).

Measurement instrumentation specifications are given in five new parts of CISPR 16-1, while the methods of measurement are covered now in four new parts of CISPR 16-2. Various reports with further information and background on CISPR and radio disturbances in general are given in CISPR 16-3. CISPR 16-4 contains information related to uncertainties, statistics and limit modelling.

CISPR 16-4 consists of the following parts, under the general title *Specification for radio disturbance and immunity measuring apparatus and methods - Uncertainties, statistics and limit modelling*:

- Part 4-1: Uncertainties in standardised EMC tests,
- Part 4-2: Uncertainty in EMC measurements,
- Part 4-3: Statistical considerations in the determination of EMC compliance of mass-produced products,
- Part 4-4: Statistics of complaints and a model for the calculation of limits.

TABLE RECAPITULATING CROSS-REFERENCES

First edition of CISPR 16-3 Clauses, subclauses	First edition of CISPR 16-4-3 Clauses
1.1	1
1.2	2
1.3	3
2.3	4
2.2	5
2.4	6

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SPECIFICATION FOR RADIO DISTURBANCE AND IMMUNITY MEASURING APPARATUS AND METHODS –

Part 4-3: Uncertainties, statistics and limit modelling – Statistical considerations in the determination of EMC compliance of mass-produced products

1 Scope

This part of CISPR 16 contains recommendations on statistics of disturbance complaints, on the significance of CISPR limits, and specific reports.

Over the years, the CISPR prepared a number of recommendations and reports that have significant technical merit but were not generally available. Reports and recommendations were for some time published in CISPR 7 and 8.

At its meeting in Campinas, Brazil, in 1988, subcommittee A agreed on the table of contents of the first edition of part 3 and to publish the reports for posterity by giving the reports a permanent place in part 3. In 2003, the relevant clauses on statistics were transferred to CISPR 16-4-3.

2 Normative references

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

CISPR 16-1:2003 (all parts), *Specification for radio disturbance and immunity measuring apparatus and methods – Radio disturbance and immunity measuring apparatus*

CISPR 16-2:2003 (all parts), *Specification for radio disturbance and immunity measuring apparatus and methods – Methods of measurement of disturbances and immunity*

CISPR 16-3:2003, *Specification for radio disturbance and immunity measuring apparatus and methods – Part 3: CISPR technical reports*

CISPR 16-4-1:2003, *Specification for radio disturbance and immunity measuring apparatus and methods – Part 4-1: Uncertainties, statistics and limit modelling – Uncertainties in standardized EMC tests*

CISPR 16-4-2:2003, *Specification for radio disturbance and immunity measuring apparatus and methods – Part 4-2: Uncertainties, statistics and limit modelling – Measurement instrumentation uncertainties*

CISPR 16-4-4:2003, *Specification for radio disturbance and immunity measuring apparatus and methods – Part 4-4: Uncertainties, statistics and limit modelling – Statistics of complaints and a model for the calculation of limits*

3 Definitions

For the purpose of this part of CISPR 16, the definitions of CISPR 16-1 and IEC 60050(161) as well as the following definitions apply.

3.1 bandwidth (B_n)

width of the overall selectivity curve of the receiver between two points at a stated attenuation, below the midband response. The bandwidth is represented by the symbol B_n , where n is the stated attenuation in decibels

3.2 impulse bandwidth (B_{imp})

$$B_{\text{imp}} = A(t)_{\text{max}} / (2G_0 \times IS)$$

where

$A(t)_{\text{max}}$ is the peak of the envelope at the IF output of the receiver with an impulse area IS applied at the receiver input;

G_0 is the gain of the circuit at the centre frequency.

Specifically, for two critically coupled tuned transformers,

$$B_{\text{imp}} = 1,05 \times B_6 = 1,31 \times B_3$$

where B_6 and B_3 are respectively the bandwidths at the -6 dB and -3 dB points

3.3 impulse area (sometimes called impulse strength) (IS)

the voltage-time area of a pulse defined by the integral:

$$IS = \int_{-\infty}^{+\infty} V(f)df \quad (\text{expressed in } \mu\text{Vs or dB}(\mu\text{Vs}))$$

NOTE Spectral density (D) is related to impulse area and expressed in $\mu\text{V}/\text{MHz}$ or $\text{dB}(\mu\text{V})/\text{MHz}$. For rectangular impulses of pulse duration T at frequencies $f \ll 1/T$, the relationship $D (\mu\text{V}/\text{MHz}) = 2 \times 10^6 / IS (\mu\text{Vs})$ applies since D is calibrated in r.m.s. values of a corresponding sine wave.

3.4 electrical charge time constant (T_C)

time needed after the instantaneous application of a constant sine-wave voltage to the stage immediately preceding the input of the detector for the output voltage of the detector to reach 63 % of its final value

NOTE This time constant is determined as follows. A sine-wave signal of constant amplitude and having a frequency equal to the mid-band frequency of the i.f. amplifier is applied to the input of the stage immediately preceding the detector. The indication, D , of an instrument having no inertia (for example, a cathode-ray oscilloscope) connected to a terminal in the d.c. amplifier circuit so as not to affect the behaviour of the detector, is noted. The level of the signal is chosen such that the response of the stages concerned remains within the linear operating range. A sine-wave signal of this level, applied for a limited time only and having a wave train of rectangular envelope is gated such that the deflection registered is $0,63D$. The duration of this signal is equal to the charge time of the detector.

3.5 electrical discharge time constant (T_D)

time needed after the instantaneous removal of a constant sine-wave voltage applied to the stage immediately preceding the input of the detector for the output of the detector to fall to 37 % of its initial value

NOTE The method of measurement is analogous to that for the charge time constant, but instead of a signal being applied for a limited time, the signal is interrupted for a definite time. The time taken for the deflection to fall to $0,37D$ is the discharge time constant of the detector.

3.6 mechanical time constant (T_M) of a critically damped indicating instrument

$$T_M = T_L / 2\pi$$

where T_L is the period of free oscillation of the instrument with all damping removed.

NOTE 1 For a critically damped instrument, the equation of motion of the system may be written as

$$T_M^2(d^2\alpha / dt^2) + 2T_M(d\alpha / dt) + \alpha = ki$$

where

α is the deflection;

i is the current through the instrument;

k is a constant.

It can be deduced from this relation that this time constant is also equal to the duration of a rectangular pulse (of constant amplitude) that produces a deflection equal to 35 % of the steady deflection produced by a continuous current having the same amplitude as that of the rectangular pulse.

NOTE 2 The methods of measurement and adjustment are deduced from one of the following:

- The period of free oscillation having been adjusted to $2\pi T_M$, damping is added so that $\alpha_{TM} = 0,35 \alpha_{max}$.
- When the period of oscillation cannot be measured, the damping is adjusted to be just below critical such that the overshoot is not greater than 5 % and the moment of inertia of the movement is such that $\alpha_{TM} = 0,35 \alpha_{max}$.

3.7 overload factor

ratio of the level that corresponds to the range of practical linear function of a circuit (or a group of circuits) to the level that corresponds to full-scale deflection of the indicating instrument.

The maximum level at which the steady-state response of a circuit (or group of circuits) does not depart by more than 1 dB from ideal linearity defines the range of practical linear function of the circuit (or group of circuits).

3.8 symmetric voltage

in a two-wire circuit, such as a single-phase mains supply, the symmetric voltage is the radio-frequency disturbance voltage appearing between the two wires. This is sometimes called the differential mode voltage. If V_a is the vector voltage between one of the mains terminals and earth and V_b is the vector voltage between the other mains terminal and earth, the symmetric voltage is the vector difference ($V_a - V_b$)

3.9 asymmetric voltage

radio-frequency disturbance voltage appearing between the electrical mid-point of the mains terminals and earth. It is sometimes called the common-mode voltage and is half the vector sum of V_a and V_b , i.e. $(V_a + V_b)/2$.

3.10 unsymmetric voltage

amplitude of the vector voltage, V_a or V_b defined in 3.8 and 3.9. This is the voltage measured by the use of an artificial mains V-network

3.11 CISPR indicating range

range specified by the manufacturer which gives the maximum and the minimum meter indications within which the receiver meets the requirements of this part of CISPR 16